Sear	cii Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/735,926	SHIRAISHI ET AL.	
Examiner	Art Unit	
Dahorah Chacko-Davis	1756	

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
(118/52)-text search only-see search history print out	4/13/2007	DCD
EAST (US-PGPUB, USPAT, FPRS, EPO, JPO, DERWENT, IBM-TDB)-see search history print out	4/14/2007	DCD
Consulted with Mr. Ram Kackar	4/9/2007	DCD
eDAN inventor search performed	4/13/2007	DCD
Search history print out	4/16/2007	DCD